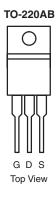


Power MOSFET

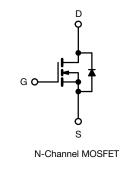
PRODUCT SUMMARY				
V _{DS} (V)	200			
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	0.20		
Q _g max. (nC)	70			
Q _{gs} (nC)	13			
Q _{gd} (nC)	39			
Configuration	Single			

FEATURES

- Surface mount
- Low-profile through-hole
- Available in tape and reel
- Dynamic dV/dt rating
- 150 °C operating temperature
- · Fast switching
- Fully avalanche rated



DRAIN connected to TAB



ABSOLUTE MAXIMUM RATINGS (T _C :	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	200	V
Gate-Source Voltage			V _{GS}	± 20	v
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 °C$	T _C = 25 °C T _C = 100 °C	I _D	14	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C		10	А
Pulsed Drain Current ^{a, e}			I _{DM}	56	
Linear Derating Factor				1.0	W/°C
Single Pulse Avalanche Energy ^{b, e}			E _{AS}	580	mJ
Avalanche Current ^a			I _{AR}	15	Α
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ
Maximum Power Dissipation	T _C =	25 °C	D	110	W
	T _A =	25 °C	P _D	3.1	vv
Peak Diode Recovery dV/dt ^{c, e}			dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak temperature) ^d	for	10 s		300	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 2.7 mH, $R_g = 25 \Omega$, $I_{AS} = 18$ A (see fig. 12). c. $I_{SD} \le 18$ A, $dI/dt \le 150$ A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.

- d. 1.6 mm from case.
- e. Uses IRF640, SiHF640 data and test conditions.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB mounted, steady-state) ^a	R _{thJA}	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μΑ	200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA ^c	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		1.0	-	3.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 V$		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$\frac{V_{DS} = 200 \text{ V}, \text{ V}_{GS} = 0 \text{ V}}{V_{DS} = 160 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}}$		-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{DS} = 100 V$ $V_{GS} = 10 V$	$I_{\rm D} = 11 {\rm A}^{\rm b}$	-	0.20	0.25	Ω
Forward Transconductance	9fs		= 50 V, I _D = 11 A ^d	6.7	-	-	S
Dynamic	915	•05		0.1		L	
Input Capacitance	C _{iss}		V = 0.V	-	1300	-	
Output Capacitance	C _{oss}		$V_{GS} = 0 V,$ $V_{DS} = 25 V,$	-	430	-	рF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5 ^d		-	130	-	- F.
Total Gate Charge	Qa			-	-	70	
Gate-Source Charge	Q _{qs}	V _{GS} = 10 V	I _D = 18 A, V _{DS} = 160 V, see fig. 6 and 13 ^{b, c}	-	-	13	nC
Gate-Drain Charge	Q _{qd}		see lig. 6 and 13 ^{b, 6}	-	-	39	
Turn-On Delay Time	t _{d(on)}			-	14	-	
Rise Time	t _r	V_{DD} = 100 V, I _D = 18 A, R _g = 9.1 Ω , R _D = 5.4 Ω , see fig. 10 ^{b, c}		-	51	-	ns
Turn-Off Delay Time	t _{d(off)}			-	45	-	
Fall Time	t _f			-	36	-	1 1
Gate Input Resistance	Rg	f = 1 MHz, open drain		0.5	-	3.6	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	18	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	72	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 18 A, V _{GS} = 0 V ^b		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}			-	300	610	ns
Body Diode Reverse Recovery Charge	Q _{rr}	- T _J = 25 °C, I _F = 18 A, dl/dt = 100 A/µs ^{b, c}		-	3.4	7.1	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is dor	ninated b	y L _S and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.

c. Uses IRF640/SiHF640 data and test conditions.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

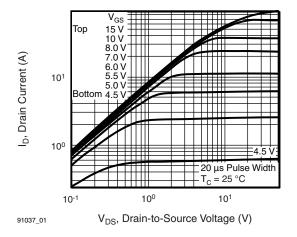


Fig. 1 - Typical Output Characteristics, T_J = 25 °C

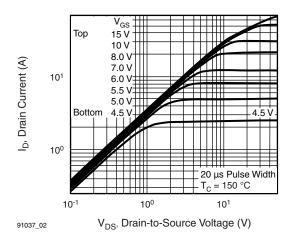


Fig. 2 - Typical Output Characteristics, T_J = 175 °C

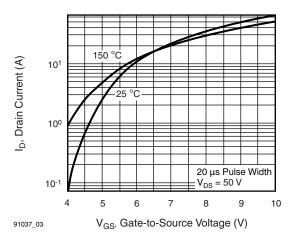


Fig. 3 - Typical Transfer Characteristics

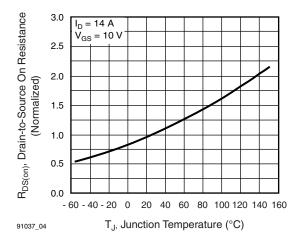


Fig. 4 - Normalized On-Resistance vs. Temperature

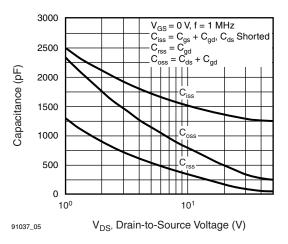


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

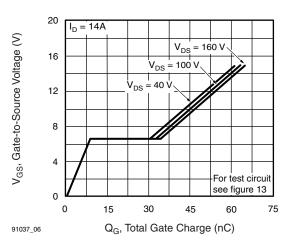


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

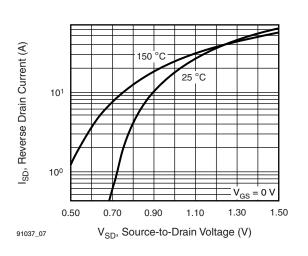


Fig. 7 - Typical Source-Drain Diode Forward Voltage

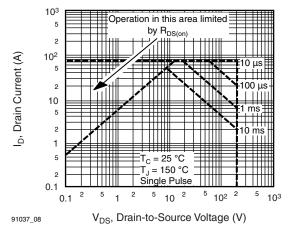
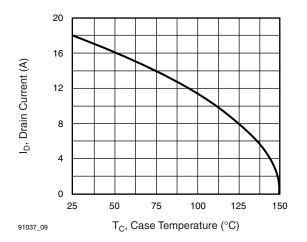


Fig. 8 - Maximum Safe Operating Area



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Fig. 9 - Maximum Drain Current vs. Case Temperature

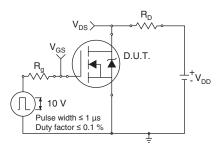


Fig. 10a - Switching Time Test Circuit

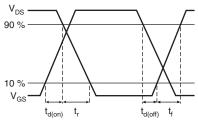
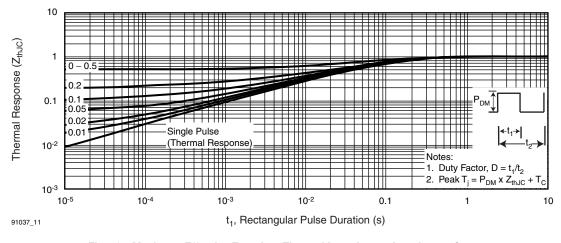


Fig. 10b - Switching Time Waveforms







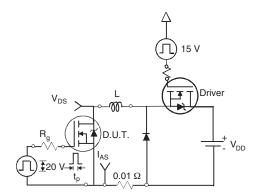


Fig. 12a - Unclamped Inductive Test Circuit

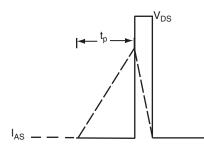


Fig. 12b - Unclamped Inductive Waveforms

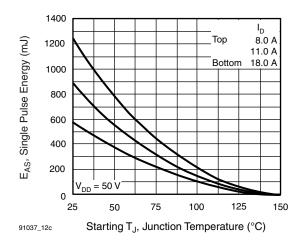


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

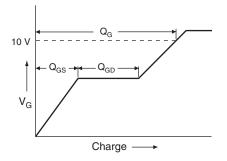


Fig. 13a - Basic Gate Charge Waveform

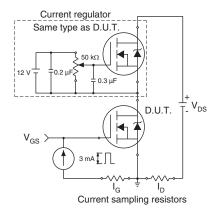
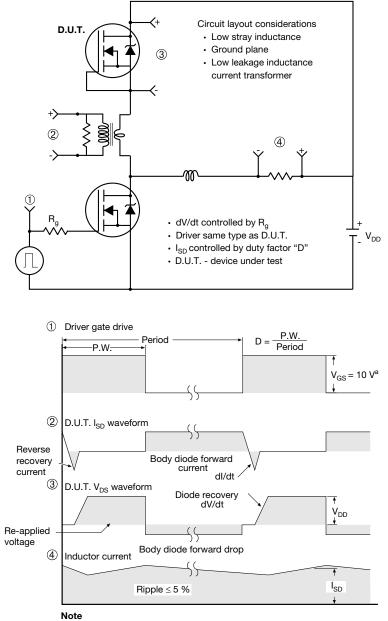


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

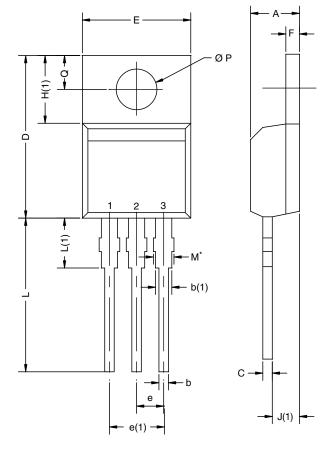


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



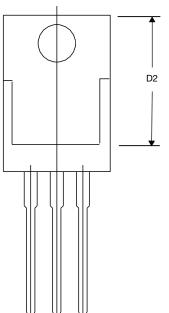
TO-220AB



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
D2	12.19	12.70	0.480	0.500
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

Note

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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